	ESC	C	D	DCUMENT	CHANGE REQUEST
DCR number	587	Changes required	for: Qua	lification	Originator: JB Sauveplane
Date: 2010/04/08 Date sent: 2010/04/08			4/08		Organisation: CNES
Status: IMPLEMENTED					
Title:	Connectors, Electrical, Rectangular, Microminiature, Non-Removable Gauge, 26 PCB Pin Contacts,				
Number:	3401/081	Issue:		2	
Other documents affected:					
3401/083-2					
Page:					
3401/081 page 25 table 6 3401/082 page 21 table 6 3401/083 page 14 table 6					
Paragraph:					
3401/081 page 25 table 6 3401/082 page 21 table 6 3401/083 page 14 table 6					
Original wording:					
Proposed wording:					
Ad in Table 6 Item 11:					
In columm 4: Rated current contact resistance drift In columm 5: Table 2, Item 2 In columm 6: DeltaRcr In columm 8: 1 In columm 9: mOhm					
Justification:					
For item n°11 there is no specified rated current contact resistance increase after the high temperature storage test. CNES proposal is to allowed a +1 mOhm drift of rated contact resistance after high temperature storage test. Thus maximum rated current contact resistance allowed would be 6 mOhm. This modification is mandatory for the qualification of Souriau microcomp connector has during high temperature storage qualification tests maximum rated current contact resistance measurements was 5.2mOhm on few contacts.					

Attachments:

N/A

Modifications:

Proposed Wording of Change is amended as follows:

1/ For 3401/083 Table 6 Item 11, remove from the "Rated Current Contact Resistance" line Column 5 "Table 2, Item 2" and replace with "6mOhm Maximum" in the Limits and Units Columns.

2/ No change to 3401/082 is actually required. Spec is mentioned in this DCR because it is related to 3401/083.

3/ For 3401/081 Table 6 Item 10, remove from the "Rated Current Contact Resistance" line Column 5 "Table 2, Item 4" and replace with "6mOhm Maximum" in the Limits and Units Columns.

Approval signature:

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Date signed:

2010-04-08